**ON Semiconductor** 

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# Onsemi

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**ON Semiconductor®** 

# FGB20N60SFD-F085 600V, 20A Field Stop IGBT

# Features

- · High current capability
- Low saturation voltage: V<sub>CE(sat)</sub> = 2.2V @ I<sub>C</sub> = 20A
- High input impedance
- · Fast switching
- Qualified to Automotive Requirements of AEC-Q101
- RoHS complaint

# Applications

- Inverters, SMPS, PFC, UPS
- Automotive Chargers, Converters, High Voltage Auxiliaries



# **General Description**

Using novel field-stop IGBT technology, ON Semiconductor's new series of field-stop IGBTs offers the optimum performance for automotive chargers, inverters, and other applications where low conduction and switching losses are essential.





# Absolute Maximum Ratings

Symbol	Description		Ratings	Units	
V <sub>CES</sub>	Collector to Emitter Voltage		600	V	
V <sub>GES</sub>	Gate to Emitter Voltage		$\pm20$	V	
	Collector Current	@ T <sub>C</sub> = 25°C	40	A	
	Collector Current	@ T <sub>C</sub> = 100 <sup>o</sup> C	20	A	
CM (1)	Pulsed Collector Current	@ T <sub>C</sub> = 25°C	60	А	
l-	Diode Forward Current	@ T <sub>C</sub> = 25 <sup>o</sup> C	20	A	
	Diode Forward Current	@ T <sub>C</sub> = 100°C	10	A	
I <sub>FM(1)</sub>	Pulsed Diode Maximum Forward Cu	d Diode Maximum Forward Current num Power Dissipation $@ T_C = 25^{\circ}C$		A	
Pn	Maximum Power Dissipation	@ T <sub>C</sub> = 25 <sup>o</sup> C	208	W	
Ū	Maximum Power Dissipation	@ T <sub>C</sub> = 100°C	600   ± 20   40   20   60   20   60   20   10   60   208   83   -55 to +150   -55 to +150   300   Ratings   0.6	W	
TJ	Operating Junction Temperature		-55 to +150	°C	
T <sub>stg</sub>	Storage Temperature Range		-55 to +150	°C	
TL	Maximum Lead Temp. for soldering Purposes, 1/8" from case for 5 second	nds	300	°C	
Thermal C	haracteristics				
Symbol	Parameter		Ratings	Units	
$R_{\theta JC}(IGBT)_{(2)}$	Thermal Resistance, Junction to Ca	se	0.6	°C/W	
	The second Descisters of the stice to Os		0.0	00.00	

O	Deveneter	<b>T</b>	1
	Deven stor	2.0 To um	
Raio(Diode)	Thermal Resistance Junction to Case	26	°C/W
		0.0	0/ •••

Device N	larking	Device	Package	Packaging Type	Qty per Tube		Max Qty per Box		
FGB20N60SFD		FGB20N60SFD-F085	TO-263	Tube	50ea		-		
Electric	al Cha	racteristics of the	<b>IGBT</b> T <sub>C</sub> = 25°	C unless otherwise noted			1		
Symbol		Parameter	Test	Conditions	Min.	Тур.	Max.	Units	
Off Charac	toristics								
BVoro	Collector	to Emitter Breakdown Voltag		= 250µA	600	_	-	V	
$\Delta BV_{CES}$ $\Delta T_{\perp}$	Temperat Voltage	ure Coefficient of Breakdow	<sup>n</sup> $V_{GE} = 0V, I_C$	$V_{GE} = 0V, I_C = 250 \mu A$		0.79	-	V/ºC	
I <sub>CES</sub>	Collector Cut-Off Current		V <sub>CE</sub> = V <sub>CES</sub> ,	V <sub>CE</sub> = V <sub>CES</sub> , V <sub>GE</sub> = 0V		-	250		
						_	250	μA	
	G-E Leak	age Current	Ver = Vere	$V_{} = 0V$		-	+400	nA	
IGES			VGE - VGES,	$v_{GE} = v_{GES}, v_{CE} = 0v$		-	1400	IIA	
On Charac	teristics								
V <sub>GE(th)</sub>	G-E Thre	shold Voltage	I <sub>C</sub> = 250μA, \	/ <sub>CE</sub> = V <sub>GE</sub>	4.0	4.8	6.5	V	
	Callastan			I <sub>C</sub> = 20A, V <sub>GE</sub> = 15V		2.2	2.85	V	
V <sub>CE(sat)</sub>			e I <sub>C</sub> = 20A, V <sub>GE</sub> T <sub>C</sub> = 125°C	$I_{C} = 20A, V_{GE} = 15V,$ $T_{C} = 125^{\circ}C$		2.4	-	V	
Dynamic C	haracteris	stics							
C <sub>ies</sub>	Input Cap	pacitance				940	1250	pF	
C <sub>oes</sub>	Output Capacitance		$V_{CE} = 30V_{V_{CE}}$	V <sub>CE</sub> = 30V, V <sub>GE</sub> = 0V, f = 1MHz		110	146	pF	
C <sub>res</sub>	Reverse	Transfer Capacitance				40	53	pF	
Switching	Character	istics							
t <sub>d(on)</sub>	Turn-On I	Delay Time			-	10	13	ns	
t <sub>r</sub>	Rise Time	9			-	16	21	ns	
t <sub>d(off)</sub>	Turn-Off I	Delay Time	V <sub>CC</sub> = 400V,	$V_{CC} = 400V, I_C = 20A,$ $R_G = 10\Omega, V_{GE} = 15V,$		90	120	ns	
t <sub>f</sub>	Fall Time		R <sub>G</sub> = 10Ω, V <sub>C</sub>			24	36	ns	
E <sub>on</sub>	Turn-On	Switching Loss	Inductive Loa	id, T <sub>C</sub> = 25°C	-	0.31	0.41	mJ	
E <sub>off</sub>	Turn-Off	Switching Loss			-	0.13	0.21	mJ	
E <sub>ts</sub>	Total Swit	tching Loss			-	0.44	0.59	mJ	
t <sub>d(on)</sub>	Turn-On I	Delay Time			-	12	16	ns	
t <sub>r</sub>	Rise Time	e			-	16	21	ns	
d(off)	Turn-Off I	Delay Time	V <sub>CC</sub> = 400V,	I <sub>C</sub> = 20A,	-	95	126	ns	
t <sub>f</sub>	Fall Time		$R_G = 10\Omega, V_G$	- ∋E = 15V,	-	28	43	ns	
E <sub>on</sub>	Turn-On S	Switching Loss	Inductive Loa	ia, 1 <sub>C</sub> = 125°C	-	0.45	0.60	mJ	
E <sub>off</sub>	Turn-Off	Switching Loss			-	0.21	0.38	mJ	
E <sub>ts</sub>	Total Swit	tching Loss			-	0.66	0.88	mJ	
Q <sub>g</sub>	Total Gate	e Charge			-	63	95	nC	
Q <sub>ge</sub>	Gate to E	mitter Charge	$V_{CE} = 400V,$ $V_{OE} = 15V/$	l <sub>C</sub> = 20A,	-	7	11	nC	
0	Gate to C	Collector Charge	VGE - 15V		-	32	48	nC	

Symbol	Parameter	Test Condition	Min.	Тур.	Max	Units	
V <sub>FM</sub>	Diode Forward Voltage	I <sub>F</sub> = 10A	T <sub>C</sub> = 25°C	-	1.9	2.5	V
			T <sub>C</sub> = 125 <sup>o</sup> C	-	1.7	-	
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>ES</sub> = 10A, dI <sub>ES</sub> /dt = 200A/μs	T <sub>C</sub> = 25°C	-	111	-	ns
			T <sub>C</sub> = 125°C	-	204	-	
Q <sub>rr</sub>	Diode Reverse Recovery Charge		T <sub>C</sub> = 25°C	-	174	244	nC
			T <sub>C</sub> = 125 <sup>o</sup> C	-	463	-	

Notes: 1: Repetitive rating: Pulse width limited by max. junction temperature

2:Rthjc for D2-PAK: according to Mil standard 883-1012 test method.

Rthja for D2-PAK: according to JESD51-2, test method environmental condition and JESD51-3, low effective thermal conductivity test board for leaded surface mount package. thermal measurements. JESD51-2: Integrated Circuits Thermal Test Method Environmental Conditions - Natural Convection (Still Air).

# **Typical Performance Characteristics**





Figure 3. Typical Saturation Voltage Characteristics



Figure 5. Saturation Voltage vs. Case Temperature at Variant Current Level



Figure 2. Typical Output Characteristics



**Figure 4. Transfer Characteristics** 



Figure 6. Saturation Voltage vs. V<sub>GE</sub>



# Typical Performance Characteristics Figure 7. Saturation Voltage vs. $V_{GE}$











Figure 8. Saturation Voltage vs. V<sub>GE</sub>



Figure 10. Gate charge Characteristics



Figure 12. Turn-on Characteristics vs. Gate Resistance









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